L Number	Hits	Search Text	DB	Time stamp
1	494	33/645.ccls.	USPAT	2003/07/02 07:09
2	2131	430/22,311.ccls.	USPAT	2003/07/02 07:09
3	489	356/399.ccls.	USPAT	2003/07/02 07:09
4	0	250/491.2.ccls.	USPAT	2003/07/02 07:09
5	1136	438/706,717,725.ccls.	USPAT	2003/07/02 07:10
6	4195	33/645.ccls. 430/22,311.ccls. 356/399.ccls. 250/491.2.ccls. 438/706,717,725.ccls.	USPAT	2003/07/02 07:10
7	405	(33/645.ccls. 430/22,311.ccls. 356/399.ccls. 250/491.2.ccls. 438/706,717,725.ccls.) and alignment near mark$1	USPAT	2003/07/02 07:11
–	6399	alignment near mark$1 and semiconductor	USPAT; US-PGPUB; EPO; JPO; DERWENT	2003/07/02 07:09
–	1787	(alignment near mark$1 and semiconductor) and photoresist	USPAT; US-PGPUB; EPO; JPO; DERWENT	2003/06/17 08:02
–	559	expose$3 near7 (alignment near mark$1) and semiconductor	USPAT; US-PGPUB; EPO; JPO; DERWENT	2003/06/17 08:07
–	1427	expos$3 near7 (alignment near mark$1) and semiconductor	USPAT; US-PGPUB; EPO; JPO; DERWENT	2003/06/17 08:07
–	1210	expos$3 near5 (alignment near mark$1) and semiconductor	USPAT; US-PGPUB; EPO; JPO; DERWENT	2003/06/17 08:07
–	471	(expos$3 near5 (alignment near mark$1) and semiconductor) and photoresist	USPAT; US-PGPUB; EPO; JPO; DERWENT	2003/06/17 09:07
–	146	clear$3 near5 (alignment near mark$1) and semiconductor	USPAT; US-PGPUB; EPO; JPO; DERWENT	2003/06/17 08:08
–	69	(clear$3 near5 (alignment near mark$1) and semiconductor) and photoresist	USPAT; US-PGPUB; EPO; JPO; DERWENT	2003/06/17 08:08
–	77	(clear$3 near5 (alignment near mark$1) and semiconductor) not ((clear$3 near5 (alignment near mark$1) and semiconductor) and photoresist)	USPAT; US-PGPUB; EPO; JPO; DERWENT	2003/06/17 08:11
–	0	chung near chieh and aligment near mark$1	USPAT; US-PGPUB; EPO; JPO; DERWENT	2003/06/17 08:11
–	0	chuang near chieh and aligment near mark$1	USPAT; US-PGPUB; EPO; JPO; DERWENT	2003/06/17 08:12
–	1	chuang near chieh and alignment near mark$1	USPAT; US-PGPUB; EPO; JPO; DERWENT	2003/06/17 08:12
–	249	lin and alignment near mark$1	USPAT; US-PGPUB; EPO; JPO; DERWENT	2003/06/17 08:12
–	121	(lin and alignment near mark$1) and photoresist	USPAT; US-PGPUB; EPO; JPO; DERWENT	2003/06/17 08:12
–	3	("6057206" | "6197481" | "6207966").PN.	USPAT	2003/06/17 08:44

–		16	("4981529" | "5382545" | "5407763" | "5596230" | "5686761" | "5705080" | "5733711" | "5858588" | "5882980" | "5904563" | "5923996" | "5926720" | "5943587" | "6060787" | "6100158" | "6143622").PN.	USPAT	2003/06/17 08:47
–		13	("3783044" | "5128283" | "5316966" | "5356513" | "5578519" | "5627110" | "5877562" | "5889335" | "5893744" | "5911108" | "5946583" | "5950093" | "5982044").PN.	USPAT	2003/06/17 08:58
–		435	((expos$3 near5 (alignment near mark$1) and semiconductor) and photoresist) not (clear$3 near5 (alignment near mark$1) and semiconductor)	USPAT; US-PGPUB; EPO; JPO; DERWENT	2003/06/17 09:08
–		13	(("6197481") or ("6184104") or ("6529274") or ("6049137") or ("4632724") or ("6057206") or ("5897371") or ("5899738") or ("5946583") or ("5627110") or ("5316966") or ("5902707") or ("5705320")).PN.	USPAT	2003/06/23 13:26